

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Yeo, et al.

Attorney Docket: TSM03-0553

Filed:

September 22, 2003

Examiner:

Unknown

Serial No.:

10/667,871

Art Unit:

2811

For:

Resistor with Reduced Leakage

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicant wishes to bring to the attention of the Patent and Trademark Office the information noted on the enclosed form PTO/SB/08A & 08B that may be considered material to the examination of the above-identified application.

Cites A-P are being filed under the waived requirement of 37 CFR 1.98(a)(2)(i) dated July 11, 2003; therefore, copies of these U.S. patents are not included. Cites Q-X, non-U.S. patents, are attached.

No fee is due at this time, as this Information Disclosure Statement is being filed pursuant to 37 C.F.R. § 1.97(b)(1), within three months of the filing date of a national application other than a continued prosecution application under § 1.53(d).

Respectfully submitted,

December 22, 2003

Date

Attorney for Applicant

Reg. No. 35,272

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				Application Number	10/667,871	
	INFORMATIO	N DISCLO	DSURE	Filing Date	September 22, 2003	
	STATEMENT	<b>BY APPL</b>	ICANT	First Named Inventor	Yeo, et al.	
				Art Unit	2811	
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U.S. PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Document Number  Number - Kind Code <sup>2 (if known)</sup>	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Whe Relevant Passages or Releva Figures Appear			
	Α	US-4,314,269	02-02-1982	Fuiiki	, iguies / ippea.			
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FOREIGN PATENT DOCUMENTS									
Examiner		Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,				
Initials*	Cite No.1	Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> ( <i>if known</i> )	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>			
	ď	WO 03/017336 A2	02-27-2003	Amberwave Systems Corporation					

OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite <sub>1</sub> No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	τ²			
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Examiner	Date	-"
Signature	Considered	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

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				Examiner Name	Unknown			
Sheet	2	of	2	Attorney Docket Number	TSM03-0553			

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OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the  Cite, No.  Item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue  number(s), publisher, city and/or country where published.				
	U	BLAAUW, D., et al., "Gate Oxide and Subthreshold Leakage Characterization, Analysis and Optimization," date unknown.			
	V	"Future Gate Stack," International Sematech, 2001 Annual Report.	Wild to the second seco		
<del>. '</del>	W	CHANG, L., et al., "Reduction of Direct-Tunneling Gate Leakage Current in Double-Gate and Ultra-Thin Body MOSFETs," 2001 IEEE, Berkeley, CA.			
	Х	CHANG, L., et al., "Direct-Tunneling Gate Leakage Current in Double-Gate and Ultrathin Body MOSFETs," 2002 IEEE, Vol. 49, No. 12, December 2002.			
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20231\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation it not in conformance and not considered. Include copy of this form with next communication to applicant.

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